



# HYM5V64804A Z-Series

SO DIMM 8Mx64 bit CMOS DRAM MODULE  
based on 8Mx8 DRAM, EDO, 3.3V, 4K/8K-Refresh

## DESCRIPTION

The HYM5V64804A Z-Series is a 8Mx64-bit EDO mode CMOS DRAM module consisting of eight 8Mx8 TSOP and one 2048-bit EEPROM on a 144 pin glass-epoxy printed circuit board. 0.1 $\mu$ F and 0.01 $\mu$ F decoupling capacitors are mounted for each DRAM. The HYM5V64804AZ G-series is gold plated socket type Dual In-line Memory Module suitable for easy interchange and addition of 64M byte memory.

## FEATURES

- Max. Active Power Dissipation

Speed	8K	4K
50	3.17W	4.03W
60	2.59W	3.46W

- Fast access time and cycle time

Speed	tRAC	tCAC	tHPC
50	50ns	13ns	25ns
60	60ns	15ns	30ns

- 144-Pin SO DIMM
- Serial Presence Detect with EEPROM
- Extended Data Out Operation

- Single power supply of 3.3V  $\pm$  10%
- Read-Modify-Write Capability
- LVTTTL compatible inputs and outputs
- /CAS-before-/RAS, /RAS-only, Hidden and Self refresh capability
- Refresh cycles

Part No.	Ref.
HYM5V64804A Z-Series	4K
HYM5V64834A Z-Series	8K $\ddagger$ <sup>a</sup>

$\ddagger$  /CAS-before-/RAS refresh, Hidden refresh mode : 4K cycles / 64ms

## PIN DISCRIPTION

/RAS0	Row Address Strobe
/CAS0-CAS7,	Column Address Strobe
/WE	Write Enable
/OE	Output Enable
A0 -A12	Address Input(8K Product)
A0 -A11	Address Input(4K Product)
DQ0-DQ63	Data Input / Output
SCL	Serial PD Clock Input
SDA	Serial PD Data Input/Output
VCC	Power (+3.3V)
VSS	Ground

**PIN NAME**

#	NAME	#	NAME	#	NAME	#	NAME
1	Vss	2	Vss	73	/OE	74	NC
3	DQ0	4	DQ32	75	Vss	76	Vss
5	DQ1	6	DQ33	77	NC	78	NC
7	DQ2	8	DQ34	79	NC	80	NC
9	DQ3	10	DQ35	81	Vcc	82	Vcc
11	Vcc	12	Vcc	83	DQ16	84	DQ48
13	DQ4	14	DQ36	85	DQ17	86	DQ49
15	DQ5	16	DQ37	87	DQ18	88	DQ50
17	DQ6	18	DQ38	89	DQ19	90	DQ51
19	DQ7	20	DQ39	91	Vss	92	Vss
21	Vss	22	Vss	93	DQ20	94	DQ52
23	/CAS0	24	/CAS4	95	DQ21	96	DQ53
25	/CAS1	26	/CAS5	97	DQ22	98	DQ54
27	Vcc	28	Vcc	99	DQ23	100	DQ55
29	A0	30	A3	101	Vcc	102	Vcc
31	A1	32	A4	103	A6	104	A7
33	A2	34	A5	105	A8	106	A11
35	Vss	36	Vss	107	Vss	108	Vss
37	DQ8	38	DQ40	109	A9	110	*A12
39	DQ9	40	DQ41	111	A10	112	NC
41	DQ10	42	DQ42	113	Vcc	114	Vcc
43	DQ11	44	DQ43	115	/CAS2	116	/CAS6
45	Vcc	46	Vcc	117	/CAS3	118	/CAS7
47	DQ12	48	DQ44	119	Vss	120	Vss
49	DQ13	50	DQ45	121	DQ24	122	DQ56
51	DQ14	52	DQ46	123	DQ25	124	DQ57
53	DQ15	54	DQ47	125	DQ26	126	DQ58
55	Vss	56	Vss	127	DQ27	128	DQ59
57	NC	58	NC	129	Vcc	130	Vcc
59	NC	60	NC	131	DQ28	132	DQ60
61	NC	62	NC	133	DQ29	134	DQ61
63	Vcc	64	Vcc	135	DQ30	136	DQ62
65	NC	66	NC	137	DQ31	138	DQ63
67	/WE	68	NC	139	Vss	140	Vss
69	/RAS0	70	NC	141	SDA	142	SCL
71	NC	72	NC	143	Vcc	144	Vcc

**NOTE :**

1.A12 is used for 8K-Refresh Product (HYM5V64834A Z-Series)

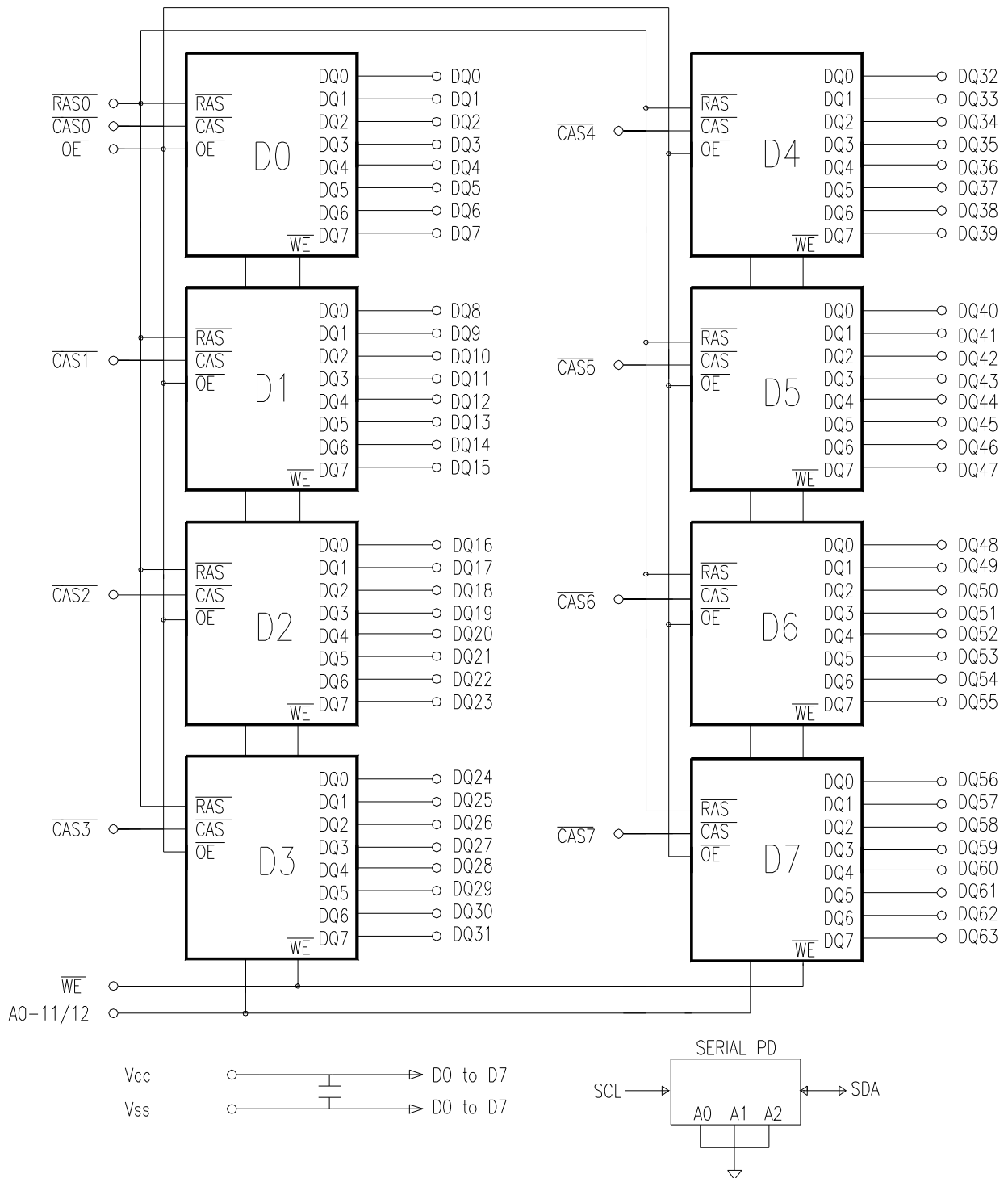
**SERIAL PRESENCE DETECT**

BYTE NUMBER	FUNCTION DESCRIBED	FUNCTION		VALUE
BYTE0	# of Byte Written into Serial Memory at Module Manufacturer	128 Bytes		80h
BYTE1	Total # of Bytes of SPD Memory Device	256 Bytes		08h
BYTE2	Fundamental Memory Type	EDO		02h
BYTE3	# of Row Addresses on This Assembly	12(4K Ref)		0Ch
		13(8K Ref)		0Dh
BYTE4	# of Column Addresses on This Assembly	11(4K Ref)		0Bh
		10(8K Ref)		0Ah
BYTE5	# of Module Banks on This Assembly	1 Bank		01h
BYTE6	Data Width of This Assembly	64 Bits		40h
BYTE7	Data Width of This Assembly(Continued)	-		00h
BYTE8	Voltage Interface Standard of This Assembly	LVTTL		01h
BYTE9	tRAC	50ns		32h
		60ns		3Ch
BYTE10	tCAC	13ns		0Dh
		15ns		0Fh
BYTE11	DIMM Configuration Type	None		00h
BYTE12	Refresh Rate/Type	4K/8K Ref, Normal(15.6μs)		00h
		4K/8K Ref, SL-Part(31.25μs)		83h
BYTE13	Primary DRAM Width	x8		08h
BYTE14	Error Checking DRAM Width	None		00h
BYTE15-61	Undefined	Undefined		FFh
BYTE62	SPD Data Revision Code	Initial		00h
BYTE63	Checksum for Byte 0-62	4K/8K Ref. Normal(15.6μs)	50ns	FBh
			60ns	07h
		4K/8K Ref. SL-Part(31.25μs)	50ns	7Eh
			60ns	8Ah
BYTE64-125	Manufacturer Data Field	HYUNDAI MFD		-
BYTE126-127	Reserved	Reserved		FFh
BYTE128-255	Undefined	Undefined		FFh

**NOTE :**

- 1.Serial PD interface is standard IIC architecture.
- 2.Pull-up resistors(4.7K typical value) are required on all open collector bus devices(SCL and SDA).
- 3.Current sink capability on SCL and SDA (Iol max) must be at least 3mA to maintain a valid low level.
- 4.Checksum can be obtained by adding the binary values in Byte 0-62, and eliminate all but low order byte.  
The low order byte would be the `Checksum`.
- 5.Refer to HYUNDAI Manufacturer Data SPEC for Byte 64-125.

**BLOCK DIAGRAM**



**NOTE :**  
 1.A12 is used for 8K-Refresh Product (HYM5V64834A Z-Series)

**ABSOLUTE MAXIMUM RATINGS**

SYMBOL	PARAMETER	RATING	UNIT
T <sub>A</sub>	Ambient Temperature	0 to 70	°C
T <sub>STG</sub>	Storage Temperature	-55 to 150	°C
V <sub>IN</sub> , V <sub>OUT</sub>	Voltage on Any Pin relative to V <sub>SS</sub>	-0.5 to 4.6	V
V <sub>CC</sub>	Voltage on V <sub>CC</sub> relative to V <sub>SS</sub>	-0.5 to 4.6	V
I <sub>OS</sub>	Short Circuit Output Current	50	mA
P <sub>D</sub>	Power Dissipation	8	W
T <sub>SOLDER</sub>	Soldering Temperature•Time	260•10	°C•sec

Note: Operation at or above Absolute Maximum Ratings can adversely affect device reliability.

**RECOMMENDED DC OPERATING CONDITIONS**

(T<sub>A</sub>=0°C to 70°C)

SYMBOL	PARAMETER	MIN.	TYP.	MAX.	UNIT
V <sub>CC</sub>	Power Supply Voltage	3.0	3.3	3.6	V
V <sub>IH</sub>	Input High Voltage	2.0	-	V <sub>CC</sub> +0.3	V
V <sub>IL</sub>	Input Low Voltage	-0.3	-	0.8	V

Note: All voltages are referenced to V<sub>SS</sub>.

**DC CHARACTERISTICS**

 (T<sub>A</sub>=0°C to 70°C , V<sub>CC</sub>=3.3V ± 10%, V<sub>SS</sub>=0V, unless otherwise noted.)

Symbol	Parameter	Test Conditions	Speed	Max. Current		Unit
				8K Product	4K Product	
I <sub>CC1</sub>	Operating Current	/RAS, /CAS Cycling t <sub>RC</sub> =t <sub>RC</sub> (min.)	50 60	880 720	1120 960	mA
I <sub>CC2</sub>	LVTTL Standby Current	/RAS = /CAS ≥ V <sub>IH</sub> other inputs ≥ V <sub>SS</sub>		8	8	mA
I <sub>CC3</sub>	/RAS-only Refresh Current	/RAS cycling /CAS = V <sub>IH</sub> t <sub>RC</sub> = t <sub>RC</sub> (min.)	50 60	880 720	1120 960	mA
I <sub>CC4</sub>	EDO Mode Current	/CAS cycling /RAS = V <sub>IL</sub> t <sub>HPC</sub> = t <sub>HPC</sub> (min.)	50 60	960 800	1040 880	mA
I <sub>CC5</sub>	CMOS Standby Current	/RAS = /CAS ≥ V <sub>CC</sub> - 0.2V	SL-part	4 2.4	4 2.4	mA
I <sub>CC6</sub>	/CAS-before-/RAS Refresh Current	t <sub>RC</sub> =t <sub>RC</sub> (min.)	50 60	880 720	1120 960	mA
I <sub>CC7</sub>	Battery Back-up Current (SL-part)	V <sub>IH</sub> = V <sub>CC</sub> - 0.2V, V <sub>IL</sub> = 0.2V /CAS = CBR cycling or 0.2V /OE & /WE = V <sub>IH</sub> = V <sub>CC</sub> - 0.2V Address = Don't care DQs = Open, t <sub>RC</sub> =31.25 μs		4.4	4.4	mA
I <sub>CC8</sub>	Self Refresh Current (SL-part)	/RAS & /CAS = 0.2V Other pins are same as I <sub>CC7</sub>		3.6	3.6	mA

Symbol	Parameter	Test Condition	Min.	Max	Unit
I <sub>LI</sub>	Input Leakage current(Any Input)	V <sub>SS</sub> ≤ V <sub>IN</sub> ≤ V <sub>CC</sub> + 0.3, All other pins not under test=V <sub>SS</sub>	-40	40	μA
I <sub>LO</sub>	Output Leakage current(Any Input)	V <sub>SS</sub> ≤ V <sub>OUT</sub> ≤ V <sub>CC</sub> /RAS & /CAS at V <sub>IH</sub>	-5	5	μA
V <sub>OL</sub>	Output Low Voltage	I <sub>OL</sub> = 2.0mA	-	0.4	V
V <sub>OH</sub>	Output High Voltage	I <sub>OH</sub> = -2.0mA	2.4	-	V

**NOTE**

- I<sub>CC1</sub>, I<sub>CC3</sub>, I<sub>CC4</sub> and I<sub>CC6</sub> dependent on output loading and cycle rates(t<sub>RC</sub> and t<sub>HPC</sub>).
- Specified values are obtained with outputs unloaded.
- I<sub>CC</sub> is specified as an average current. In I<sub>CC1</sub>, I<sub>CC3</sub>, I<sub>CC6</sub>, address can be changed only once while /RAS=V<sub>IL</sub>. In I<sub>CC4</sub>, address can be changed maximum once while /CAS=V<sub>IH</sub> within one EDO mode cycle time t<sub>HPC</sub>.
- Only /RAS(max.) = 1μs is applied to refresh of battery backup but t<sub>RAS</sub>(max.) = 10μs is applied to normal functional operation.
- I<sub>CC5</sub>(max.) = 2.4mA, I<sub>CC7</sub> and I<sub>CC8</sub> are applied to SL-part only.
- V<sub>OH</sub> = 2.0V, V<sub>OL</sub> = 0.8V at AC Functional Test.

**AC CHARACTERISTICS**

 (T<sub>A</sub>=0°C to 70°C , V<sub>cc</sub>=3.3V ± 10%, V<sub>ss</sub>=0V, unless otherwise noted.)

#	SYMBOL	PARAMETER	HYH5V64804A / HYM5V64834A						UNIT	NOTE
			-50		-60		-70			
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
1	tRC	Random Read or Write Cycle Time	90	-	110	-			ns	
2	tRWC	Read-Modify-Write Cycle Time	128	-	153	-			ns	
3	tHPC	EDO Mode Cycle Time	25	-	30	-			ns	
4	tHPRWC	EDO Mode Read-Modify-Write Cycle Time	67	-	73	-			ns	
5	tRAC	Access Time from /RAS	-	50	-	60			ns	4,5,10,11
6	tCAC	Access Time from /CAS	-	13	-	15			ns	4,5,10
7	tAA	Access Time from Column Address	-	25	-	30			ns	4,5,11
8	tCPA	Access Time from /CAS Precharge	-	28	-	35			ns	4
9	tCLZ	/CAS to Output Low Impedance	3	-	3	-			ns	3
10	tCEZ	Output Buffer Turn-off delay from /CAS	3	13	3	13			ns	
11	tT	Transition Time (Rise and Fall)	2	50	2	50			ns	4
12	tRP	/RAS Precharge Time	30	-	40	-			ns	
13	tRAS	/RAS Pulse Width	50	10K	60	10K			ns	
14	tRASP	/RAS Pulse Width (EDO Mode)	50	100K	60	100K			ns	
15	tRSH	/RAS Hold Time	13	-	15	-			ns	
16	tCSH	/CAS Hold Time	40	-	45	-			ns	
17	tCAS	/CAS Pulse Width	8	10K	10	10K			ns	
18	tRCD	/RAS to /CAS Delay	17	37	20	45			ns	10
19	tRAD	/RAS to Column Address Delay Time	13	25	15	30			ns	11
20	tCRP	/CAS to /RAS Precharge Time	5	-	5	-			ns	
21	tCP	/CAS Precharge Time	8	-	10	-			ns	
22	tASR	Row Address Set-up Time	0	-	0	-			ns	
23	tRAH	Row Address Hold Time	8	-	10	-			ns	
24	tASC	Column Address Set-up Time	0	-	0	-			ns	
25	tCAH	Column Address Hold Time	8	-	10	-			ns	
26	tAR	Column Address Hold Time from /RAS	45	-	50	-			ns	
27	tRAL	Column Address to /RAS Lead Time	25	-	30	-			ns	
28	tRCS	Read Command Set-up Time	0	-	0	-			ns	
29	tRCH	Read Command Hold Time Referenced to /CAS	0	-	0	-			ns	7
30	tRRH	Read Command Hold Time Referenced to /RAS	0	-	0	-			ns	7
31	tWCH	Write Command Hold Time	10	-	10	-			ns	
32	tWCR	Write Command Hold Time from /RAS	40	-	45	-			ns	
33	tWP	Write Command Pulse Width	8	-	10	-			ns	
34	tRWL	Write Command to /RAS Lead Time	15	-	15	-			ns	
35	tCWL	Write Command to /CAS Lead Time	8	-	10	-			ns	

**AC CHARACTERISTICS**

(Continued)

#	SYMBOL	PARAMETER	HYH5V64804A / HYM5V64834A						UNIT	NOTE
			-50		-60		-70			
			MIN.	MAX.	MIN.	MAX.	MIN.	MAX.		
36	tDS	Data-In Set-up Time	0	-	0	-			ns	8
37	tDH	Data-In Hold Time	10	-	10	-			ns	8
38	tDHR	Data-In Hold Time Referenced to /RAS	40	-	45	-			ns	
39	tREF	Refresh Period (8192 cycles)	-	64	-	64			ms	12,13
		Refresh Period (4096 cycles)	-	64	-	64			ms	12
		Refresh Period (SL-part)	-	128	-	128			ms	12,13
40	tWCS	Write Command Set-up Time	0	-	0	-			ns	9
41	tCWD	/CAS to /WE Delay Time	34	-	36	-			ns	9
42	tRWD	/RAS to /WE Delay Time	70	-	80	-			ns	9
43	tAWD	Column Address to /WE Delay Time	45	-	50	-			ns	9
44	tCSR	/CAS Set-up Time (CBR Cycle)	5	-	5	-			ns	
45	tCHR	/CAS Hold Time (CBR Cycle)	10	-	10	-			ns	
46	tRPC	/RAS to /CAS Precharge Time	5	-	5	-			ns	
47	tCPT	/CAS Precharge Time (CBR Counter Test)	25	-	30	-			ns	
48	tROH	/RAS Hold Time Referenced to /OE	0	-	0	-			ns	
49	tOEA	/OE Access Time	-	13	-	15			ns	
50	tOED	/OE to Data Delay	13	-	15	-			ns	
51	tOEZ	Output Buffer Turn-Off Delay Time from /OE	0	10	0	15			ns	6
52	tOEH	/OE Command Hold Time	13	-	15	-	-	--	ns	
53	tCPWD	/WE Delay Time from /CAS Precharge	45	-	54	-			ns	9
54	tRHCP	/RAS Hold Time from /CAS Precharge	30	-	35	-			ns	
55	tWRP	/WE to /RAS Precharge Time(CBR cycle)	10	-	10	-			ns	
56	tWRH	/WE to /RAS Hold Time (CBR cycle)	10	-	10	-			ns	
57	tWTS	Write Command Set-up Time (Test Mode In)	10	-	10	-			ns	
58	tWTH	Write Command Hold Time (Test Mode In)	10	-	10	-			ns	
59	tRASS	/RAS Pulse Width (Self Refresh)	100K	-	100K	-			us	
60	tRPS	/RAS Precharge Time (Self Refresh)	100	-	100	-			ns	
61	tCHS	/CAS Hold Time (Self Refresh)	-50	-	-50	-			ns	
62	tDOH	Output Data Hold Time	5	-	5	-			ns	
63	tREZ	Output Buffer Turn-off Delay from /RAS	0	10	0	15			ns	6
64	tWEZ	Output Buffer Turn-off Delay from /WE	0	10	0	15			ns	6
65	tWED	/WE to Data Delay Time	15	-	15	-			ns	
66	tOEP	/OE Precharge Time	5	-	5	-			ns	
67	tWPE	/WE Pulse Width (EDO cycle)	5	-	5	-			ns	
68	tOCH	/OE to /CAS Hold Time	5	-	5	-			ns	
69	tCHO	/CAS Hold Time to /OE	5	-	5	-			ns	



**NOTE**

1. An initial pause of 200 $\mu$ s is required after power-up followed by 8 /RAS cycles before proper device operation is achieved. In case of using internal refresh counter, a minimum of 8 /CAS-before-/RAS initialization cycles instead of 8 /RAS-only refresh cycles are required. The device should be carefully initialized to be prevented from being entered into multi bit test mode during initialization.
2. If /RAS=Vss during power-up, the HYM5V64804A / HYM5V64834A could begin an active cycle. This condition results in higher current than necessary current which is demanded from the power supply during power-up.
3. It is recommended that /RAS and /CAS track with Vcc during power-up or be held at a valid VIH in order to minimize the power-up current.
4. VIH(min.) and VIL(max.) are reference levels for measuring timing of input signals. Transition times are measured between VIH(min.) and VIL(max.), and are assumed to be 5ns for all inputs.
5. Measured at VOH=2.0V and VOL=0.8V with a load equivalent to 1 TTL loads and 100pF.
6. tWEZ, tREZ, tCEZ and tOEZ define the time at which the output achieves the open circuit condition and is not referenced to output voltage levels.
7. Either tRCH or tRRH must be satisfied for a read cycle.
8. These parameters are referenced to /CAS leading edge in early write cycles and to /WE leading edge in Read-Modify-Write cycles and late Write cycle.
9. tWCS, tRWD, tCWD, tAWD and tCPWD are not restrictive operating parameters. They are included in the data sheet as electrical characteristics only. If tWCS  $\geq$  tWCS(min.), the cycle is an early write cycle and data out pin will remain open circuit (high impedance) through the entire cycle. If tRWD  $\geq$  tRWD(min.), tCWD  $\geq$  tCWD(min.), tAWD  $\geq$  tAWD(min.), and tCPWD  $\geq$  tCPWD(min.), the cycle is a Read-Modify-Write cycle and data out will contain data read from the selected cell. If neither of the above sets of conditions is satisfied, the condition of the data out (at access time) is indeterminate.
10. Operation within the tRCD(max.) limit ensures that tRAC(max.) can be met. tRCD(max.) is specified as a reference point only. If tRCD is greater than the specified tRCD(max.) limit, then access time is controlled by tCAC.
11. Operation within the tRAD(max.) limit ensures that tRAC(max.) can be met. tRAD(max.) is specified as a reference point only. If tRAD is greater than the specified tRAD(max.) limit, then access time is controlled by tAA.
12. tREF(max.)=128ms is applied to SL-parts.
13. A burst of 8192 /RAS-only refresh cycles must be executed within 64ms (128ms for SL-parts) after exiting self refresh. (CBR refresh & Hidden refresh : 4K cycle/64ms)

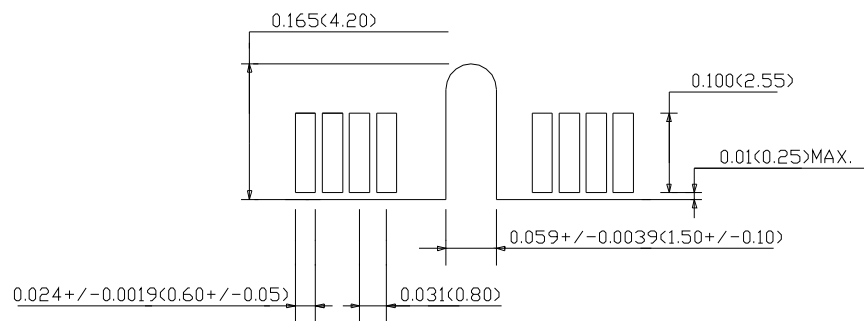
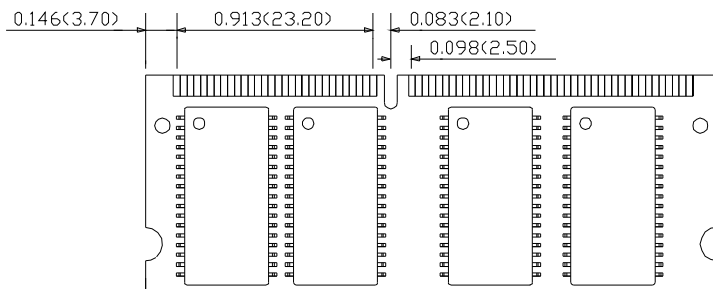
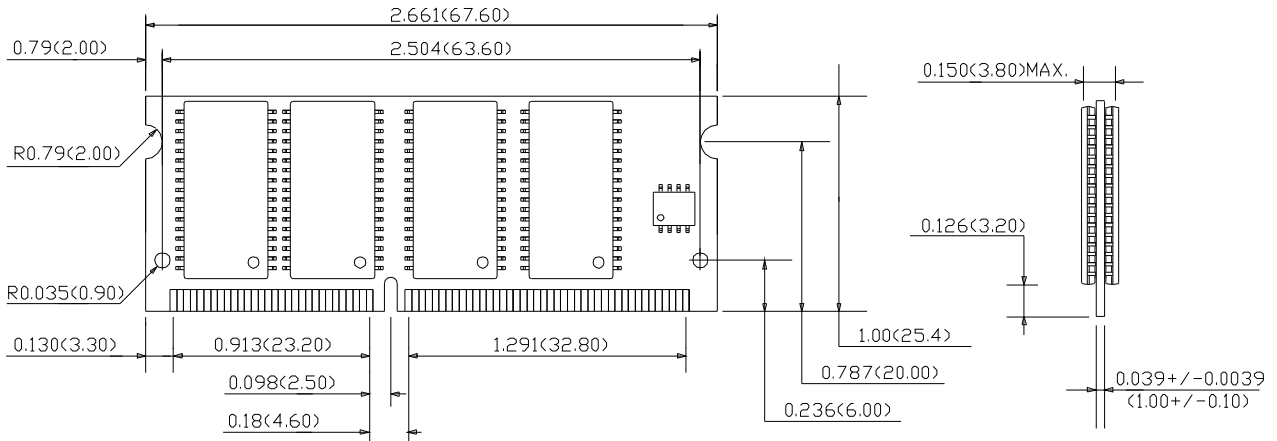
**CAPACITANCE**

(TA=0°C to 70°C , Vcc=3.3V  $\pm$  10%, Vss=0V, f = 1MHz, unless otherwise noted.)

SYMBOL	PARAMETER	TYP.	MAX.	UNIT
CIN1	Input Capacitance (A0 - A12)	-	50	pF
CIN2	Input Capacitance (/WE, /OE)	-	65	pF
CIN3	Input Capacitance (/RAS0)	-	65	pF
CIN4	Input Capacitance (/CAS0 - /CAS7)	-	14	pF
CDQ	Data Input /Output Capacitance (DQs)	-	14	pF

**PACKAGE INFORMATION**

UNIT : INCH(mm)  
TOLERANCE : +/-0.0059(0.15)



**ORDERING INFORMATION**

<b>Part Number</b>	<b>Ref.</b>	<b>Power</b>	<b>Package</b>
HYM5V64804ATZG	4K	Normal	TSOP
HYM5V64804ASLTZG	4K	SL-part	TSOP
HYM5V64834ATZG	8K	Normal	TSOP
HYM5V64834ASLTZG	8K	SL-part	TSOP